

Search Notes**Application/Control No.**

10/558,841

Examiner

/Yonel Beaulieu/

**Applicant(s)/Patent under
Reexamination**

TOBIYAMA ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	200-202	3/1/2010	YB
	211		
	28		
	25		
340	995.1		
	995.19		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR